In re Patent Application of:

CROCE ET AL.

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TABLE 2

region	Dopant	Thickness	Doping [Atoms
		[µm]	cm ⁻³]
n-body (conductivity "N")	phosphorous	0.25-0.75	5x10 ¹⁷ -5x10 ¹⁸
body-buffer	boron	0.15-0.45	5x10 ¹⁶ -5X10 ¹⁷
(conductivity "P")		below	
		junction	
		with n-	
		body	
drain well region	boron	1.5-4.5	2.5x10 ¹⁵ -2.5x10 ¹⁶
(conductivity "P")		below	
		junction	
		with body-	
		buffer	

In the Claims:

Please amend Claims 5 and 14 as follows:

- 5. (Amended) A lateral diffused metal oxide semiconductor (LDMOS) integrated device comprising:
 - a semiconductor substrate;
- a drain region of a first conductivity type adjacent said semiconductor substrate and comprising a superficial buffer region being more heavily doped than adjacent portions of said drain region;
- a body region surrounded by said buffer region and having a second conductivity type; and
- a source region in said body region and having the first conductivity type.



14. (Amended) A lateral diffused metal oxide semiconductor (LDMOS) integrated device comprising: